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OMB No. 0651-0011

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<b>INFORMATION DISCLOSURE STATEMENT</b>	Atty. Docket No.: 150.01150103	Serial No.: 10/771,043
	Applicant(s): Gurtej S. Sandhu	Confirmation No.: Unassigned
	Application Filing Date: February 3, 2004	Group: Unassigned
	Information Disclosure Statement mailed:	April 29, 2004

**U.S. PATENT DOCUMENTS**

Examiner Initial	Copy Entered	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
46		3,585,073	06/15/71	Veenstra et al.			
		3,890,703	06/75	Frazee et al.			
		4,433,320	02/21/84	Murata et al.			
		4,442,422	04/10/84	Murata et al.			
		4,677,416	06/30/87	Nishimoto et al.			
		4,911,892	03/27/90	Grace et al.			
		5,147,737	09/15/92	Post et al.			
		5,331,287	07/19/94	Yamagishi et al.			
		5,337,018	08/09/94	Yamagishi			
		5,756,879	05/26/98	Yamagishi et al.			
		5,857,250	01/12/99	Riley et al.			
		5,906,726	05/25/99	Schneider et al.			
		6,280,604	08/28/01	Allen et al.			
		6,436,246	08/20/02	Sandhu			
		6,479,297	11/12/02	Sandhu			
		6,689,321	02/10/04	Sandhu			
		US 2003/0138958	07/24/03	Blalock			

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Copy Entered	Document Number	Date	Country	Class	Subclass	Translation Yr	No
		1,151,482	05/07/69	Great Britain				
		1,576,658	08/01/69	France (w/abstract)				X

<b>EXAMINER</b> <i>Jelen Yeh</i>	<b>Date Considered</b> <i>05/26/03</i>
*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609: Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

PAGE 4/7 \* RCVD AT 4/29/2004 4:10:51 PM [Eastern Daylight Time] \* SVR:USPTO-EFXXF-1/0 \* DNIS:8729306 \* CSID:1 612 305 1228 \* DURATION (mm:ss):03:16

PAGE 7/9 \* RCVD AT 12/9/2004 1:50:37 PM [Eastern Standard Time] \* SVR:USPTO-EFXXF-1/0 \* DNIS:8729306 \* CSID:6123051228 \* DURATION (mm:ss):02:50

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<b>INFORMATION DISCLOSURE STATEMENT</b>	Atty. Docket No.: 150.01150103	Serial No.: 10/771,043
	Applicant(s): Gurtej S. Sandhu	Confirmation No.: Unassigned
	Application Filing Date: February 3, 2004	Group: Unassigned
	Information Disclosure Statement mailed: April 29, 2004	

		2-293644	12/04/90	Japan (w/abstract)				X
		386,660	09/12/90	EP (w/abstract)				X
		3-48748	03/01/91	Japan (w/abstract)				X
		60-210752	10/85	Japan (w/abstract)				X
		2-69658	03/90	Japan				X

**OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)**

Examiner Initial	Copy Enclosed	Document Description
Y		Aizenshtein et al., "Method of measurement of the rate of deposition of pure metals from the gas phase," <i>Chem. Abstr.</i> , 1966; 64: abstract 1747e.
		Aizenshtein et al., "Method of Measuring Rate of Pure Metals Deposition from the gas phase," <i>Tsvetnye Metally The Soviet Journal of Non-Ferrous Metals</i> , 6(9): 72-74.
		Bardin et al., "Voltametry of Ruthenate, Determination of Ruthenium from the Electrochemical Reduction of Ruthenium," <i>Journal of Analytical Chemistry of the USSR</i> , 1975;30: 642-645.
		Bates, J.R. et al., "The influence of the electrodeposition parameters on the morphology of organo-transition metal complexes for thin film gas sensor application", <i>Thin Solid Films</i> , 1997;299: 18-24.
		Brown et al., "New method for the characterization of domain morphology of polymer blends using ruthenium tetroxide staining and low voltage scanning electron microscopy (LVSEM)," <i>Polymer</i> , 1997; 38(15): 3937-3945.
		Kawahara et al., "(Ba,Sr)TiO <sub>3</sub> Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes," <i>Jpn Journ Appl Phys</i> , 1996;35 (Part 1, No. 9B): 4880-4885.
		Kawahara et al., "(Ba, Sr)TiO <sub>3</sub> Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes," <i>J. Appl. Phys.</i> , 1996;35: 4880-4885.
✓		Koda et al., "Radioactivation determination of ruthenium," <i>Chem Abstr</i> , 1979;90: abstract 114382q.

<b>EXAMINER</b> Helew Gah	<b>Date Considered</b> 12/15/04 09/11/03 Printed 05/26/03
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PAGE 57 \* RCVD AT 4/29/2004 4:18:51 PM [Eastern Daylight Time] \* SVR:USPTO-EFXRF-1/3 \* DNIS:8729306 \* CSID:16123051228 \* DURATION (mm:ss):03:16

PAGE 8/9 \* RCVD AT 12/9/2004 1:50:37 PM [Eastern Standard Time] \* SVR:USPTO-EFXRF-1/0 \* DNIS:8729306 \* CSID:6123051228 \* DURATION (mm:ss):02:50

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<b>INFORMATION DISCLOSURE STATEMENT</b> 	Atty. Docket No.: 150.01150103	Serial No.: 10/771,043
	Applicant(s): Gurtej S. Sandhu	Confirmation No.: 1538
	Application Filing Date: February 3, 2004	Group: 1743
	Information Disclosure Statement mailed: June 16, 2004	

**U.S. PATENT DOCUMENTS**

Examiner Initial	Copy Enclosed	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
		5,653,807	08/05/97	Crumbaker			

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Copy Enclosed	Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
Y6	X	1,576,658	08/01/69	France (w/abstract)			X	
Y6	X	2-293644	12/04/90	Japan (w/abstract)			X	
Y6	X	3-48748	03/01/91	Japan (w/abstract)			X	
Y6	X	<del>2-69658</del>	<del>03/08/90</del>	<del>Japan (w/abstract)</del>				X

**OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)**

Examiner Initial	Copy Enclosed	Document Description
Y6	X	Akinfiyeva, T.A., "Basis for the maximum allowable concentration of ruthenium dioxide in the air of work areas," <i>Gigiena Truda i Professional'nye Zabolevaniya</i> , 1981:46-47 (English Abstract Included)
	X	Crawford et al., "Use of the Hazop Analysis for Evaluation of CVD reactors," <i>Journal de Physique IV</i> , September 1991: C2-459- C2-466.
	X	Gale et al., "Interaction of Safety and the facility for Photovoltaic R & D," <i>American Institute of Physics Conference Proceedings</i> , 1988;66:145-151
	X	Koda et al., "Radioactivation determination of ruthenium," <i>Kyoto Daigaku Genshiro Jikkensho Gakujutsu Koenkai Koen Yoshishyu</i> , 1976;10:25-27. (English Translation)
	X	Lu et al., "Epitaxial growth of RuO <sub>2</sub> thin films by metal-organic chemical vapor deposition," <i>Thin Solid Films</i> , 1999;340:140-144.
	X	Orlow et al., "Detection of Ruthenium in Platinum Alloys," <i>Chemiker-Zeitung</i> , 1908;32:77. (English Translation)

EXAMINER <i>Yelue Hal</i>	Date Considered <i>08/06/04</i>
<small>*Examiner Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	